

Search Notes

Application/Control No.

10/688,954

Examiner

W. David Coleman

Applicant(s)/Patent under
Reexamination

KIM ET AL.

Art Unit

2823

SEARCHED

Class	Subclass	Date	Examiner
438	14 441 687	3/2/2005	WDC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
438	14	3/2/2005	WDC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST 2.0.1; CAS STN; IEEE; Applicants claim a process of electrodeless copper deposition for analysis of defects on a wafer.	3/2/2005	WDC